Multilayer Ceramic Capacitor

- High Frequency -



NWW

INTRODUCTION

MLCC for high frequency application is made of many layers of Class I(C0G, etc) ceramic and Cu inner electrodes like sandwich. Class I(C0G, etc) ceramic has a small TCC(Temperature Coefficient of Capacitance), a better frequency performance and a low ESR(Equivalent Series Resistance) value. Therefore, it is used in RF applications such as cellular phone, tuner, and so on.

■ FEATURE AND APPLICATION

Feature

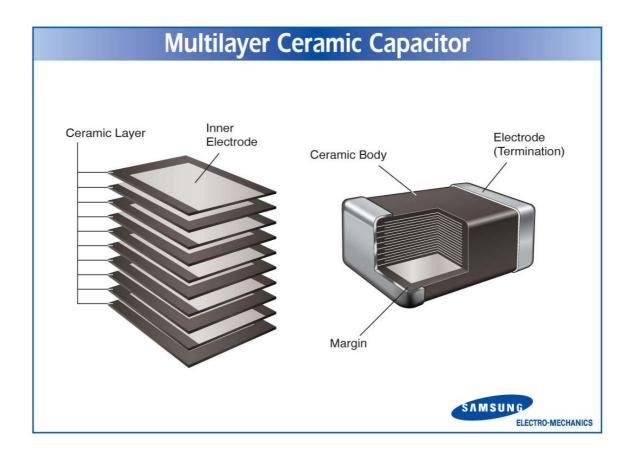
- Miniature Size
- Wide Capacitance and Voltage Range
- Highly Reliable Performance
- Tape & Reel for Surface Mount Assembly
- Low ESR
- High Q at High Frequencies
- Stable Temperature Dependence of Capacitance

Application

- High frequency module and high power circuit

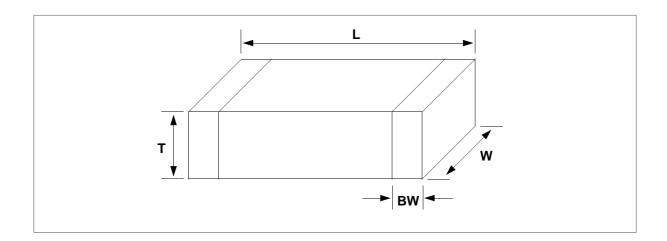


■ STRUCTURE





■ APPEARANCE AND DIMENSION



CODE	EIA CODE	DIMENSION (mm)							
OODL	LIA GODE	L	W	T (MAX)	BW				
03	0201	$0.6~\pm~0.03$	0.3 ± 0.03	0.3 ± 0.03	0.15 ± 0.05				
05	0402	1.0 ± 0.05	0.5 ± 0.05	0.5 ± 0.05	0.2+0.15/-0.1				



■ PREVIOUS PART NUMBERING

 CL
 10
 C
 101
 J
 B
 G
 C

 1
 2
 3
 4
 6
 6
 7
 8

- 1 SAMSUNG Multilayer Ceramic Capacitor
- 2 Type(Size)
- 3 Capacitance Temperature Characteristics("C" only)
- 4 Nominal Capacitance
- **6** Capacitance Tolerance
- 6 Rated Voltage
- 7 Code "G" : Cu-Inner electrode
- 8 Packaging Type

3 TEMPERATURE CHARACTERISTICS

► CLASS I (Temperature Compensating type)

Symbol	EIA Code	Temperature Coefficient(PPM/℃)	* Temperature Characteristics	Operation Temperature Range
С	C0G(CH)	0 ± 30	CΔ	-55 ~ +125°C

*** Temperature Characteristics**

Temperature Characteristics	below 2.0pF	2.2 ~ 3.9pF	2.2 ~ 3.9pF above 4.0pF above 10pF		Arr K : ±250 PPM/ $ Arr$ J : ±120 PPM/ $ Arr$
CΔ	C0G	C0G	C0G	C0G	H : ±60 PPM/℃
РΔ	-	P2J	P2H	P2H	G : ±30 PPM/℃
RΔ	-	R2J	R2H	R2H	
S∆	-	S2J	S2H	S2H	
TΔ	-	T2J	T2H	T2H	
UΔ	-	U2J	U2J	U2J	



4 NOMINAL CAPACITANCE

The nominal capacitance value is expressed in pico-farad(pF) and identified by three-digits. The first two digits represent significant figures and the last digit specifies the number of zeros to follow. For values below 1pF, the letter "R" is used as the decimal point.

example)

100 : 10 ×	10° =	10pF	
102 : 10 ×	$10^{2} =$	1000pF	
020 : 2 ×	10° =	2pF	
1R5 : 1.5pF	•		

6 CAPACITANCE TOLERANCE

Temperature Characteristics	Symbol	Capacitance tolerance	Capacitance range	capacitance step	
	В	±0.4≈⊏	0.5~2.0pF	0.1pF	
	Б	±0.1pF	2.0~5.0pF	E-24 step	
C0G(NPO)	С	±0.25pF	40-5	F 04 4	
or T.C Series	D	±0.50pF	<10pF	E-24 step	
110 001100	F	±1%	>40mF	E-24 step	
	J	±5%	≥10pF	E-12 step	

^{*} Please consult us for special tolerances.

6 RATED VOLTAGE

Symbol	Rated Voltage(Vdc)
Α	25V
В	50V

7 Type of Inner electrode

Symbol	Description of the Code
G	Copper inner electrode-standard thickness



9 PACKAGING TYPE

Symbol	Packaging	Symbol	Packaging
В	Bulk	F	Embossed Tape, 13" Reel
Р	Cassette	L	Paper 13" Reel
С	Paper Tape, 7" Reel	0	Paper 10" Reel
D	Paper Tape, 13" Reel	S	Embossed Tape, 10" Reel
E	Embossed Tape, 7" Reel		

▶ STANDARD CAPACITANCE STEP

Series	Capacitance step											
E- 3	1.0			2.2			4.7					
E- 6	1	.0 1.5 2.2		.2	3.3		4.7		6.8			
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E 24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

Standard Capacitance is " Each step ×10" "



■ NEW PART NUMBERING

 CL
 10
 C
 101
 J
 B
 8
 G
 N
 N
 C

 1
 2
 3
 6
 6
 6
 6
 6
 9
 0
 1

- 1 SAMSUNG Multilayer Ceramic Capacitor
- 2 Size(mm)
- 3 Capacitance Temperature Characteristic
- 4 Nominal Capacitance
- **6** Capacitance Tolerance
- 6 Rated Voltage
- **7** Thickness Option
- 8 Product & Plating Method
- Samsung Control Code
- 10 Reserved For Future Use
- 1 Packaging Type

1 PRODUCT ABBREVIATION

Symbol	Product Abbreviation			
CL	SAMSUNG Multilayer Ceramic Chip Capacitor			

2 SIZE(mm)

Cumbal	Size(mm)				
Symbol	Length	Width			
03	0.6	0.3			
05	1.0	0.5			



3 TEMPERATURE CHARACTERISTICS

► CLASS I (Temperature Compensating type)

Symbol	EIA Code	Temperature Coefficient(PPM/℃)	* Temperature Characteristics	Operation Temperature Range
С	C0G(CH)	0 ± 30	С	-55 ~ +125℃

***** Temperature Characteristics

Temperature Characteristics	below 2.0pF	2.2 ~ 3.9pF	above 4.0pF	above 10pF
CΔ	C0G	C0G	C0G	C0G
РΔ	-	P2J	P2H	P2H
RΔ	-	R2J	R2H	R2H
SΔ	-	S2J	S2H	S2H
TΔ	-	T2J	T2H	T2H
UΔ	-	U2J	U2J	U2J

Fig. K: ± 250 PPM/°C J: ± 120 PPM/°C H: ± 60 PPM/°C G: ± 30 PPM/°C

4 NOMINAL CAPACITANCE

Nominal capacitance is identified by 3 digits.

The first and second digits identify the first and second significant figures of the capacitance.

The third digit identifies the multiplier. 'R' identifies a decimal point.

Example

Symbol	Nominal Capacitance
1R5	1.5pF
103	10,000pF, 10nF, 0.01 μ F
104	100,000pF, 100nF, 0.1 μ F

6 CAPACITANCE TOLERANCE

Symbol	Tolerance	Nominal Capacitance		
В	±0.1pF			
С	±0.25pF	Less than 10pF (Including 10pF)		
D	±0.5pF	(morading Topi)		
F	±1%	More than 10pF		
J	±5%	More than 10pF		



RATED VOLTAGE

Symbol	Rated Voltage	Symbol	Rated Voltage	
Α	25V	В	50V	

THICKNESS OPTION

Туре	Symbol	Thickness(T)	Spec
0603	3	0.30	±0.03
1005	5	0.50	±0.05

PRODUCT & PLATING METHOD

Symbol	Electrode	Termination	Plating Type
Α	Pd	Ag	Sn_100%
N	Ni	Cu	Sn_100%
G	Cu	Cu	Sn_100%

SAMSUNG CONTROL CODE

Symbol	Description of the code	Symbol	Description of the code
A	Array (2-element)	N	Normal
В	Array (4-element)	P	Automotive
С	High - Q	W	3 Terminal EMI Filter
L	LICC		

RESERVED FOR FUTURE USE

Symbol	Description of the code
N	Reserved for future use



1 PACKAGING TYPE

Symbol	Packaging Type	Symbol	Packaging Type
В	Bulk	F	Embossing 13" (10,000EA)
Р	Bulk Case	L	Paper 13" (15,000EA)
С	Paper 7"	0	Paper 10"
D	Paper 13" (10,000EA)	S	Embossing 10"
E	Embossing 7"		



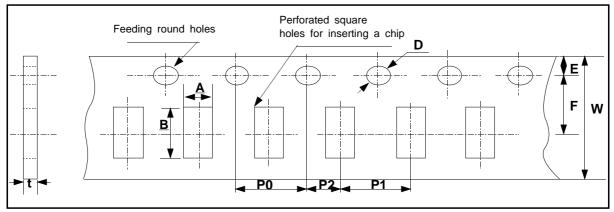
► CAPACITANCE vs CHIP THICKNESS STANDARD

D	escription		0603 type (0201)	1005 type (0402)	
Dimension(mm)		L	0.6±0.03	1.0±0.05	
		w	0.3±0.03	0.5±0.05	
		Т	0.3±0.03	0.5±0.05	
MAX	6	25V	20	-	
CAPACITANCE(pF)	APACITANCE(pF)	50V	-	10	



■ PACKAGING

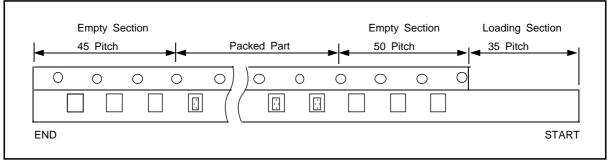
● CARDBOARD PAPER TAPE



unit: mm

	mbol ype	w	F	E	P1	P2	P0	D	t	Α	В
D i m e	03	8.0	3.5	1.75	2.0	2.0	4.0	Ф1.5	0.37 ±0.03	0.38 ±0.03	0.68 ±0.03
n s i o n	05	±0.3	±0.05	±0.1	±0.05	±0.05	±0.1	+0.1/-0	0.6 ±0.05	0.65 +0.05 -0.10	1.15 +0.05 -0.10

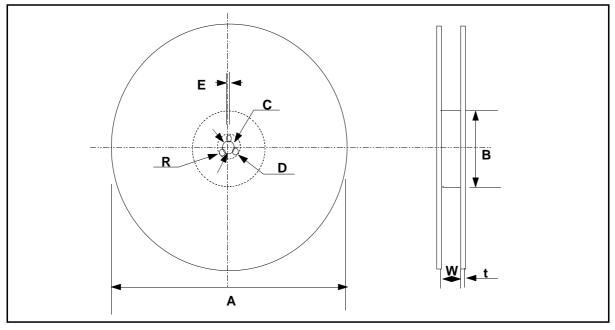
● TAPING SIZE



unit: pcs

Symbol	Cardboard Paper Tape
7" Reel	10000
13" Reel	10000

REEL DIMENSION



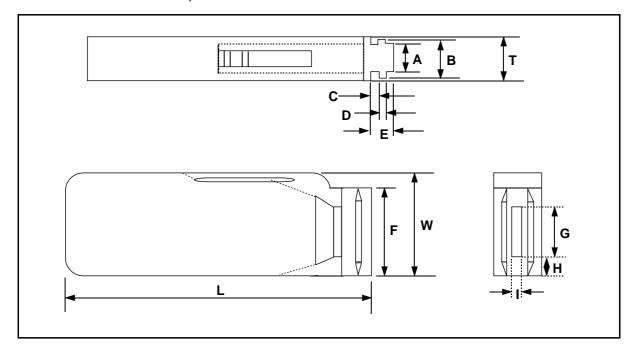
unit: mm

Symbol	Α	В	С	D	E	W	t	R
7" Reel	φ178±2.0	min.¢50						
13" Reel	ф330±2.0	min.¢70	φ13±0.5	21±0.8	2.0±0.5	10±1.5	0.8±0.2	1.0



BULK CASE PACKAGING

- Bulk case packaging can reduce the stock space and transportation costs.
- The bulk feeding system can increase the productivity.
- It can eliminate the components loss.



Symbol	Α	В	Т	С	D	E
Dimension	6.8±0.1	8.8±0.1	12±0.1	1.5+0.1/-0	2+0/-0.1	4.7±0.1
Symbol	F	W	G	Н	L	ı
Dimension	31 5+0 2/-0	36+0/-0.2	19+0.35	7+0.35	110+0.7	5+0.35

QUANTITY

Size	03(0201)	05(0402)
Quantity	N/A	50,000

^{*} N/A: Not adapted

■ CHARACTERISTIC MAP

- CAPACITANCE RANGE
- ▶ CLASS I

Temperature	Size Voltag		Capacitance Range (pF)									
Characteristics		Voltage	0.5	0 10	00 100	00 100	000 100	0000 10	00000 1	0000000	100000000	
C(COG)	03 (0201)	25V		20								
	05 (0402)	50V		10								



■ RELIABILITY TEST DATA

NO	ITEM		PERFORMANCE	TEST	CONDITION	
1	APPEARAN	ICE	NO ABNORMAL EXTERIOR APPEARANCE.	THROUGH MICROSCO	OPE(×10)	
2	INSULATION RESISTANCE		10,000 $\mathrm{M}\Omega$ OR 500 $\mathrm{M}\Omega\cdot\mu\mathrm{F}$ PRODUCT WHICHEVER IS SMALLER. (RATED VOLTAGE IS BELOW 16V : 10,000 $\mathrm{M}\Omega$ OR 100 $\mathrm{M}\Omega\cdot\mu\mathrm{F}$)	RATED VOLTAGE SH MEASUREMENT TIME RATED VOLTAGE TIM	IS 60 ~ 120se	
3	WITHSTAND VOLTAGE		NO DIELECTRIC BREAKDOWN OR MECHANICAL BREAKDOWN.	CLASS I: 300% OF THE RATED VOLTAGE FOR 1		
				CAPACITANCE	FREQUENCY	VOLTAGE
4	CAPACITANCE	CLASS I	WITHIN THE SPECIFIED TOLERANCE	1,000 pF AND BELOW	1Mb±10%	
				MORE THAN 1,000pF 1klb±10%		0.5 ~ 5 Vrms
				CAPACITANCE	FREQUENCY	VOLTAGE
5	Q	CLASS	OVER 30 pF : Q ≥1,000 LESS THAN 30 pF: Q ≥400 +20C (C : CAPACITANCE)	1,000 pF AND BELOW	1Mb±10%	0.5 ~ 5 Vrms
				MORE THAN 1,000pF	1kHz±10%	0.5 ~ 5 VIIIIS
			NO INDICATION OF PEELING OCCUR ON THE TERMINAL	A 500g.f PRESSURE APPLIED FOR 10±1 S		
6					7//// -	■500g.f
7	ESR		$2pF < C \le 5pF$: BELOW $200m\Omega$ $5pF < C \le 10pF$: BELOW $150m\Omega$ $10pF < C \le 33pF$: BELOW $100m\Omega$	TEST EQUIPMENT : I CONDITION: FREQUE ROOM TEMPERATUR	NCY 1GHz, Osc	: 100m AT



NO	IT	EM	PERFOR	MANCE		TEST CONDI	TION	
		APPEARANCE	NO MECHANICAL OCCUR.	DAMAGE SHALL		SHALL BE APF		
	BENDING		CHARACTER	CHANGE OF CAPACITANCE	50	<u>√</u> 20 R=	<u>340</u>	
8	STRENGTH	CAPACITANCE	WITHIN ±5% OR ± CLASS I 0.5pF WHICHEVER IS LARGER		BENDING LIMIT			
			MORE THAN 95% SURFACE IS TO E NEWLY, SO META NOT COME OUT	L PART(A) DOES		TEMPERATURE : 3±1 Sec : H63A	: 230±5℃	
9	SOLDE	RABILITY	-		*PB-FREE SOLDER TEMPERATURE : 260±5℃ SOLDER : Sn96.5-3Ag-0.5Cu Flux : RMA TYPE			
				T, MORE THAN 95% L SURFACE IS TO EWLY		: 3±0.1Sec ATING : AT 80-	-120℃ FOR	
		APPEARANCE	NO MECHAN	NICAL DAMAGE UR.	DIP : SOLDER TEMPERATURE OF $270\pm5^{\circ}\!$			
			CHARACTERISTIC	CAP. CHANGE				
		CAPACITANCE	CLASS I	WITHIN $\pm 2.5\%$ OR $\pm 0.25\mathrm{pF}$	IMMERSEI FOLLOWIN	D AND PREHEA	ATED AS	
	RESISTANCE TO		02.001	WHICHEVER IS LARGER	STEP	TEMP.(℃)	TIME (SEC.)	
10	SOLDERING				2	80~100 150~180	60	
	HEAT	Q CLASS I	30pF AND OVER LESS THAN 30pF			AT ROOM TE		
	_	INSULATION RESISTANCE	TO SATISFY THE INITIAL VALUE.	SPECIFIED	COOLING CLASS I	FOR : 24 ± 2 HOUR	S	
	WITHSTANDING TO SATISFY THE SPECIFIED VOLTAGE INITIAL VALUE.							



NO	ITEM		PER	FORMANCE	TEST CONDITION			
		APPEARANCE	NO MECHANICAL	DAMAGE SHALL OCCUR.	THE CAPACITOR SHALL BE			
			CHARACTERISTI	CAP. CHANGE	SUBJECTED TO A HARMONIC			
		CAPACITANCE	CLASS I	WITHIN ±2.5% OR ± 0.25pF WHICHEVER IS LARGER	MOTION HAVING A TOTAL AMPLITUDE OF 1.5mm.			
			CLASS B	WITHIN ±5%	THE ENTIRE FREQUENCY RANGE,			
	VIBRATION		II F	WITHIN ±20%	FROM 10 TO 55Hz AND RETURN			
11	TEST	Q CLASS I	30pF AND OVER LESS THAN 30pF	: Q≥ 1000	TO 10Hz, SHALL BE TRAVERSED IN 1 MINUTE. THIS CYCLE SHALL BE PERFORMED 2 HOURS IN EACH THERE			
		INSULATION RESISTANCE	TO SATISFY THE	E SPECIFIED	MUTUALLY PERPENDICULAR DIRECTION FOR TOTAL PERIOD OF 6 HOURS.			
		APPEARANCE	NO MECHANICAL	DAMAGE SHALL OCCUR.	TEMPERATURE : 40±2 ℃			
			CHARACTERISTI C	CAPACITANCE CHANGE	RELATIVE HUMIDITY: 90~95 %RH TEST TIME: 500 +12/-0 Hr.			
40	HUMIDITY (STEADY STATE)	CAPACITANCE	CLASS I	WITHIN ±5% OR ±0.5 pF WHICHEVER IS LARGER	MEASURE AT ROOM TEMPERATURE AFTER COOLING FOR			
12		Q CLASS I	30pF AND OVER 10 ~30pF : Q2 LESS THAN 10pF		CLASS I : 24±2 Hr.			
		INSULATION RESISTANCE	MINIMUM INSULA 1,000 MΩ OR 50MΩ WHICHEVER IS					
		APPEARANCE	NO MECHANICAL	DAMAGE SHALL OCCUR.	APPLIED VOLTAGE: RATED VOLTAGE TEMPERATURE: 40±2 °C RELATIVE HUMIDITY:90~95%RH TEST TIME: 500 +12/-0 Hr.			
			CHARACTERISTI	CAPACITANCE	CURRENT APPLIED : 50mA MAX.			
			С	CHANGE				
13	MOISTURE	CAPACITANCE	CLASS I	WITHIN ±7.5% OR ±0.75pF WHICHEVER IS LARGER	CLASS II SHOULD BE MEASURED INITIAL VALUE AFTER BE HEAT-TREATED FOR 1 HR IN 150°C+0/-10°C AND BE LEFT FOR			
.0	RESISTANCE	Q	30 pF AND OVER	: Q≥ 200	48±4HR AT ROOM TEMPERATURE.			
		CLASS I	30pF AND BELOW	/ : Q≥ 100 + 10/3×C	<latter measurement=""></latter>			
		INSULATION RESISTANCE	MINIMUM INSULA 500 MΩ OR 25MΩ·μ WHICHEVER IS S	•	CLASS I SHOULD BE MEASURED AFTER LEFT FOR 24±2 HRS IN ROOM TEMPERATURE AND HUMIDITY. CLASS II SHOULD BE MEASURED LATTER VALUE AFTER BE HEAT-TREATED FOR 1 HR IN 150°C+0/-10 °C AND BE LEFT FOR 48±4HR AT ROOM			



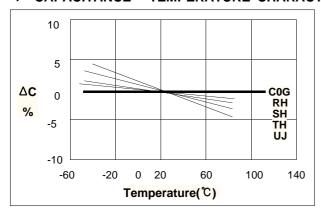
NO	ITE	EM .	PERF	ORMANCE		TEST CONDITIO	N		
		APPEARANCE	NO MECHANICAL OCCUR.	_ DAMAGE SHALL	20 TEST TI) VOLTAGE : 10% OF RATED VOL ME : 1000 +48/-0 H	r.		
			CHARACTERIS TIC CAP. CHANGE		CURREN	IT APPLIED : 50 mA 25 ± 3 °C	MAX.		
14	HIGH TEMPERATURE RESISTANCE	CAPACITANCE	CLASS I	WITHIN $\pm 3\%$ OR $\pm 0.3\mathrm{pF}$, WHICHEVER IS LARGER	<pre><initial measurement=""> CLASS II SHOULD BE MEASURED INITIAL VALUE AFTER BE HEAT-TREATED FOR 1 HR IN 150$^{\circ}$C+0/-10 $^{\circ}$C AND BE LEFT FOR 48±4HR AT ROOM TEMPERATURE.</initial></pre>				
		Q CLASS I	30 pF AND OVER 10 ~ 30 pF : C LESS THAN 10 pF		CLASS I LEFT FO	<pre>- <latter measurement=""> CLASS I SHOULD BE MEASURED AFTER LEFT FOR 24±2 HRS IN ROOM TEMPERATURE AND HUMIDITY.</latter></pre>			
		INSULATION RESISTANCE	MINIMUM INSULA 1,000 MQ OR 50M WHICHEVER IS		LATTER HEAT-TR © AND E	LATTER VALUE AFTER BE HEAT-TREATED FOR 1 HR IN 150°C+0/-10 °C AND BE LEFT FOR 48±4HR AT ROOM TEMPERATURE.			
	APPEARA		NO MECHANICAI OCCUR.	_ DAMAGE SHALL	TO FIVE	ORS SHALL BE SU CYCLES OF THE ATURE CYCLE AS ING	IBJECTED		
			CHARACTERISTI	C CAP. CHANGE	STEP	TEMP.(℃)	TIME (MIN)		
	TEMPERATURE	CAPACITANCE	CLASS I WITHIN $\pm 2.5\%$ OR $\pm 0.25\mathrm{pF}$ WHICHEVER IS LARGER		1	MIN. RATED TEMP. +0/-3	30		
15	TEMPERATURE CYCLE	Q	30 pF AND OVER	R : Q ≥ 1000	2	25	2~3		
		CLASS I	LESS THAN 30 pl	:Q ≥400 +20×C	3	MAX. RATED TEMP. +3/-0	30		
					4	25	2~3		
		INSULATION RESISTANCE	TO SATISFY THE	E SPECIFIED	AFTER (EE AT ROOM TEMP COOLING FOR LASS I : 24±2 Hr. LASS II : 48±4 Hr.	ERATURE		

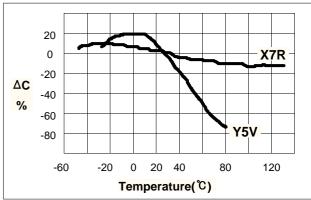


■ CHARACTERISTIC GRAPH

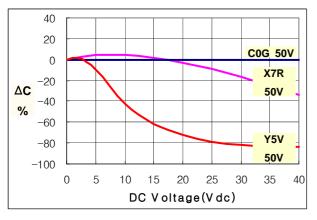
ELECTRICAL CHARACTERISTICS

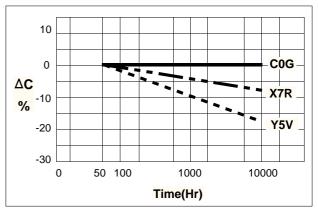
▶ CAPACITANCE - TEMPERATURE CHARACTERISTICS



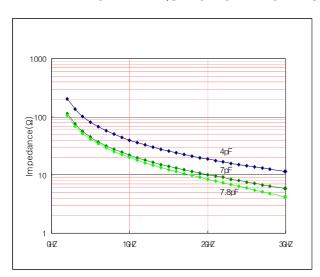


► CAPACITANCE - DC VOLTAGE CHARACTERISTICS ► CAPACITANCE CHANGE - AGING





▶ IMPEDANCE - FREQUENCY CHARACTERISTICS





APPLICATION MANUAL

Storage Condition

▶ Storage Environment

The electrical characteristics of MLCCs were degraded by the environment of high temperature or humidity. Therefore, the MLCCs shall be stored in the ambient temperature and the relative humidity of less than 40° C and 70%, respectively. Guaranteed storage period is within 6 months from the outgoing date of delivery.

Corrosive Gases

Since the solderability of the end termination in MLCC was degraded by a chemical atmosphere such as chlorin, acid or sulfide gases, MLCCs must be avoid from these gases.

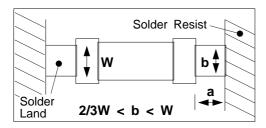
► Temperature Fluctuations

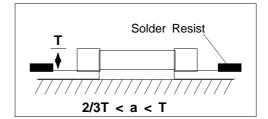
Since dew condensation may occur by the differences in temperature when the MLCCs are taken out of storage, it is important to maintain the temperature-controlled environment.

Design of Land Pattern

When designing printed circuit boards, the shape and size of the lands must allow for the proper amount of solder on the capacitor. The amount of solder at the end terminations has a direct effect on the crack. The crack in MLCC will be easily occurred by the tensile stress which was due to too much amount of solder. In contrast, if too little solder is applied, the termination strength will be insufficiently. Use the following illustrations as guidelines for proper land design.

Recommendation of Land Shape and Size





Adhesives

When flow soldering the MLCCs, apply the adhesive in accordance with the following conditions.

► Requirements for Adhesives

They must have enough adhesion, so that, the chips will not fall off or move during the handling of the circuit board.

They must maintain their adhesive strength when exposed to soldering temperature.

They should not spread or run when applied to the circuit board.

They should harden quickly.

They should not corrode the circuit board or chip material.



They should be a good insulator.

They should be non-toxic, and not produce harmful gases, nor be harmful when touched.

► Application Method

It is important to use the proper amount of adhesive. Too little and much adhesive will cause poor adhesion and overflow into the land, respectively.

► Adhesive hardening Characteristics

To prevent oxidation of the terminations, the adhesive must harden at 160° C or less, within 2 minutes or less.

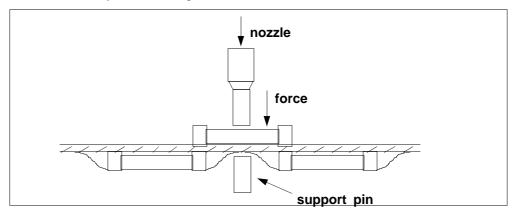
Mounting

▶ Mounting Head Pressure

Excessive pressure will cause crack to MLCCs. The pressure of nozzle will be 300g maximum during mounting.

▶ Bending Stress

When double-sided circuit boards are used, MLCCs first are mounted and soldered onto one side of the board. When the MLCCs are mounted onto the other side, it is important to support the board as shown in the illustration. If the circuit board is not supported, the crack occur to the ready-installed MLCCs by the bending stress.



Flux

Although the solderability increased by the highly-activated flux, increase of activity in flux may also degrade the insulation of the chip capacitors. To avoid such degradation, it is recommended that a mildly activated rosin flux(less than 0.2% chlorine) be used.



Soldering

Since a multilayer ceramic chip capacitor comes into direct contact with melted solder during soldering, it is exposed to potentially mechanical stress caused by the sudden temperature change. The capacitor may also be subject to silver migration, and to contamination by the flux. Because of these factors, soldering technique is critical.

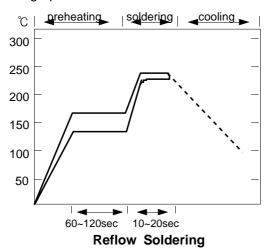
► Soldering Methods

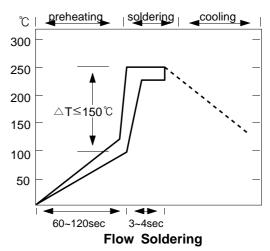
Method		Classification
Reflow	- Overall heating	Infrared raysHot plateVPS(vapor phase)
soldering	- Local heating	Air heaterLaserLight beam
Flow soldering	- Single wave - Double wave	-

^{*} We recommend the reflow soldering method.

▶ Soldering Profile

To avoid crack problem by sudden temperature change, follow the temperature profile in the adjacent graph.

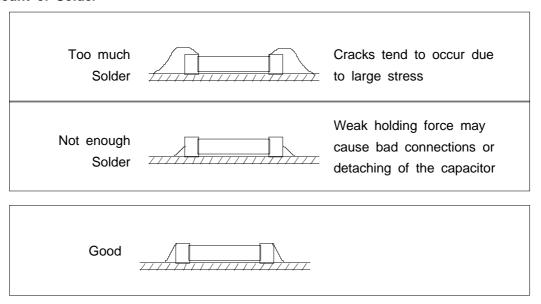




Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in chip capacitors. The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor. Therefore the soldering iron must be handled carefully, and close attention must be paid to the selection of the soldering iron tip and to temperature control of the tip.

► Amount of Solder



▶ Cooling

Natural cooling using air is recommended. If the chips are dipped into solvent for cleaning, the temperature difference($\triangle T$) must be less than 100 $^{\circ}C$

6-6. Cleaning

If rosin flux is used, cleaning usually is unnecessary. When strongly activated flux is used, chlorine in the flux may dissolve into some types of cleaning fluids, thereby affecting the chip capacitors. This means that the cleaning fluid must be carefully selected, and should always be new.

▶ Notes for Separating Multiple, Shared PC Boards.

A multi-PC board is separated into many individual circuit boards after soldering has been completed. If the board is bent or distorted at the time of separation, cracks may occur in the chip capacitors. Carefully choose a separation method that minimizes the bending of the circuit board.



■ CROSS REFERENCE

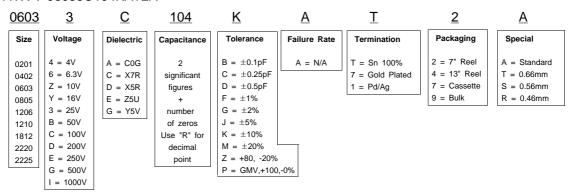
P/N	COMPANY	SAMSUNG	AVX	JOHANSON	KEMET	KYOCERA	MURATA	NOVACAP	PANASONIC	ROHM	TAIYO - YUDEN	TDK	VITRAMON
① COMPANY	MODEL(MLCC)	CL	-	-	С	СМ	GRM	-	ECJ	MCH	MK	С	۸٦
	0201(0603)	03	-	-	-	03	33	-	Z	-	063	0603	-
② SIZE (EIA/JIS)	0402(1005)	05	0402	R07	0402	05	36	0402	0	15	105	1005	0402
	0603(1608)	10	0603	R14	0603	105	39	0603	1	18	107	1608	0603
	0805(2012)	21	0805	R15	0805	21	40	0805	2	21	212	2012	0805
	1206(3216)	31	1206	R18	1206	316	42-6	1206	3	31	316	3216	1206
	1210(3225)	32	1210	S41	1210	32	42-2	1210	4	32	325	3225	1210
	1808(4520)	42	1808	R29	1808	42	-	1808	-	-	-	4520	1808
	1812(4532)	43	1812	S43	1812	43	43-2	1812	-	43	432	4532	1812
	2220(5750)	55	-	-	2220	55	44-1	2221	-	-	550	5650	-
	COG(NPO)	С	А	N	G	CG	COG/CH	N	С	Α	С	COG/CH	А
	P2H(N150)	P	s	-	-	P	P2H	-	Р	-	Р	PH	-
	R2H(N220)	R	1	-	-	R	R2H	-	R	-	R	RH	-
	S2H(N330)	S	3	-	-	S	S2H	-	S	-	S	SH	-
3	T2H(N470)	Т	0	-	-	Т	T2H	-	Т	-	Т	TH	-
TEMPERATURE CHARACTERISTIC	U2J(N750)	U	Z	-	-	U	U2J	-	U	UJ	U	UJ	-
	S2L	L	Υ	-	-	SL	SL	-	G	SL	SL	SL	-
	X7R	В	С	w	R(X)	X7R	X7R	В	В	С	BJ	X7R(B)	Y(X)
	Z5U	Е	E	Z	U	-	Z5U	z	=	E	-	Z5U	U
	Y5V	F	G	Y	V	Y5V	Y5V	Y	F	F	F	Y5V	-
Nominal	CAPACITANCE			E)	K) 103=10,0	00pF 221:	=220pF 22	5=2,200,000pF=	2.2# 1R5=1.	5pF 010=1	1 pF		
© CAPACITAN	CE TOLERANCE			B:±0.1pF C:	±0.25pF	D:±0.5pF F	F:±1% G:±	±2% J:±5%	K:±10%	M:±20%	Z:-20~+80%	6	
	6.3V	Q	6	-	9	06	6.3	-	0J	-	J	0,1	-
	10 V	Р	Z	100	8	10	10	-	1A	4	L	1A	-
	16 V	0	Υ	160	4	16	16	160	1C	3	E	1C	J
	25 V	А	3	250	3	25	25	250	1E	2	Т	1E	х
	50 V	В	5	500	5	50	50	500	1H	5	U	1H	А
	100 V	С	1	101	1	100	100	101	2A	1	-	2A	В
® RATED	200V	D	2	201	2	200	200	201	2D	-	-	-	С
VOLTAGE	250V	E	V	-	-	250	250	251	-	-	-	2E	-
	500V	G	7	501	-	500	500	501	-	-	-	-	E
	630V	Н	-	-	-	630	630	-	-	-	-	2J	-
	1000V	I	А	102	-	1000	1K	102	-	-	-	3A	G
	2000V	J	G	202	-	2000	2K	202	-	-	-	3D	-
	3000V	К	н	302	-	3000	ЗК	302	-	-	-	3F	Н
			J		-	4000	-	402	-	-	-	-	-
	4000V	-					(GRM)	N	-	(MCH)	-	_	х
(7) TERMINATION	4000V NICKEL BARRIER	N	Т	V	С	A	(Ortivi)	.,					
① TERMINATION			T 1	V -	C -	В	(GR)	P	-	(MC)	-	-	F
TERMINATION	NICKEL BARRIER	N							- X	(MC)	-		F B
	NICKEL BARRIER Ag/Pd	N P	1	-	-	В	(GR)	Р				-	
① TERMINATION ② PACKAGE	NICKEL BARRIER Ag/Pd BULK(VINYL)	N P B	1 9	- (NONE)	-	В	(GR)	P *	Х	-	В	- В	В



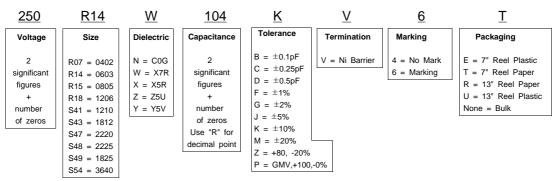
► SAMSUNG : CL10B104KA8NNNC

<u>CL</u>	<u>10</u>	<u>B</u>	<u>104</u>	<u>K</u>	<u>A</u>	<u>8</u>	<u>N</u>	<u>N</u>	<u>N</u>	<u>C</u>
Series	Size	Dielectric	Capacitance	Tolerance	Voltage	Thickness	Electrode/	Products	Special	Packaging
							Termination/			
	03 = 0201	C = C0G	2	$A = \pm 0.05pF$	Q = 6.3V	3 = 0.30	Plating	A = Array	Various	B = Bulk
	05 = 0402	P = P2H	significant	$B = \pm 0.1pF$	P = 10V	5 = 0.50		(2-element)		P = Cassette
	10 = 0603	R = R2H	figures	$C = \pm 0.25pF$	O = 16V	8 = 0.80	A = Pd/Ag/	B = Array		C = Paper 7"
	21 = 0805	S = S2H	+	$D = \pm 0.5pF$	A = 25V	A = 0.65	Sn 100%	(4-element)		D = Paper 13"
	31 = 1206	T = T2H	number	F = ±1%	B = 50V	C = 0.85	N = Ni/Cu/	C = High - Q		(10,000EA)
	32 = 1210	U = U2H	of zeros	$G = \pm 2\%$	C = 100V	H = 1.60	Sn 100%	L = LICC		E = Embossing 7"
	43 = 1812	L = S2L	Use "R" for	J = ±5%	D = 200V	I = 2.00	G = Cu/Cu/	N = Normal		F = Embossing 13"
	55 = 2220	B = X7R	decimal point	$K = \pm 10\%$	E = 250V	J = 2.50	Sn 100%	P = Automotive		L = Paper 13"
		A = X5R		$M = \pm 20\%$	G = 500V	L = 3.20		W = 3 terminal		(15,000EA)
		F = Y5V		Z = +80,-20%	H = 630V			chip		O = Paper 10"
					I = 1000V			<u> </u>	_	S = Embossing 10"

► AVX: 06033C104KAT2A



► JOHANSON: 250R14W104KV6T



► KEMET: C0603C104K3RAC

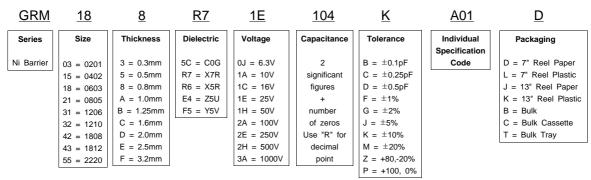
IXLIVIL	REMET : GOODG TO HOUNG												
<u>C</u>	<u>0603</u>	<u>C</u>	<u>104</u>	<u>K</u>	<u>3</u>	<u>R</u>	<u>A</u>	<u>C</u>					
Series	Size	Specification	Capacitance	Tolerance	Voltage	Dielectric	Failure Rate	Termination					
	0402 0603 0805 1206 1210 1812 2220 2225	C = Standard A = GR900 P = Mil-C-55681	2 significant figures + number of zeros Use "R" for decimal point	$B = \pm 0.1 pF$ $C = \pm 0.25 pF$ $D = \pm 0.5 pF$ $F = \pm 1\%$ $G = \pm 2\%$ $J = \pm 5\%$ $K = \pm 10\%$ $M = \pm 20\%$ $Z = +80, -20\%$	9 = 6.3V 8 = 10V 4 = 16V 3 = 25V 5 = 50V 1 = 100V 2 = 200V	G = C0G R = X7R P = X5R U = Z5U X = BX(Mil) V = Y5V	A = Standard M = 1.0 (Mil) P = 0.1 (Mil) R = 0.01 (Mil) S = 0.001 (Mil)	C = Ni w/Tin Plate H = Ni w/Solder T = Silver G = Gold Plated					
				P = +100, 0%									



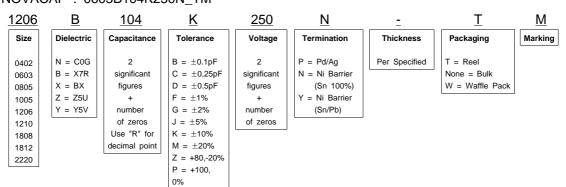
▶ KYOCERA : CM105X7R104K25AT

<u>CM</u>	<u>105</u>	<u>X7R</u>	<u>104</u>	<u>K</u>	<u>25</u>	<u>A</u>	<u>T</u>
Series	Size	Dielectric	Capacitance	Tolerance	Voltage	Termination	Packaging
	03 = 0201 05 = 0402 105 = 0603 21 = 0805 316 = 1206 32 = 1210 42 = 1808 43 = 1812 55 = 2220	CG X8R X7R X5R Z5U Y5V	2 significant figures + number of zeros Use "R" for decimal point	B = ± 0.1 pF C = ± 0.25 pF D = ± 0.5 pF F = $\pm 1\%$ G = $\pm 2\%$ J = $\pm 5\%$ K = $\pm 10\%$ M = $\pm 20\%$ Z = $+80, -20\%$ P = $+100, 0\%$	04 = 4V 06 = 6.3V 10 = 10V 16 = 16V 25 = 25V 50 = 50V 100 = 100V 250 = 250V 500 = 500V 1000 = 1000V	A = Ni Barrier	T = 7" Reel (4mm Pitch) L = 13" Reel (4mm Pitch) H = 7" Reel (2mm Pitch) N = 13" Reel (2mm Pitch) B = Bulk (Vinyl Bags) C = Bulk Cassette

► MURATA: GRM188R71E104KA01D



► NOVACAP: 0603B104K250N TM

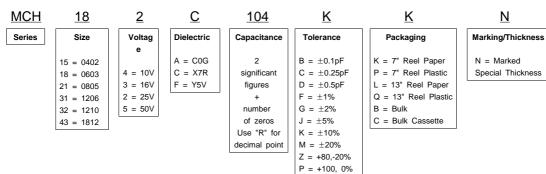


► PANASONIC : ECJ1EB1E104K

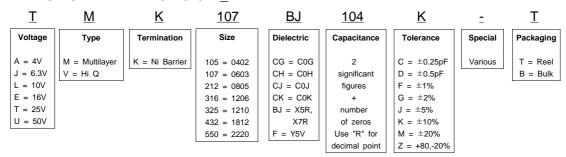
<u>ECJ</u>	<u>1</u>	<u>E</u>	<u>B</u>	<u>1E</u>	<u>104</u>	<u>K</u>
Series	Size	Packaging	Dielectric	Voltage	Capacitance	Tolerance
	Z = 0201 0 = 0402 1 = 0603 2 = 0805 3 = 1206 4 = 1210	X = Bulk E = Paper 2mm V = Paper 4mm F, Y = Plastic 4mm W = Large Reels 2mm Z = Large Reels 4mm C = Bulk Cassette	C = C0G B = X7R, X5R F = Y5V	0J = 6.3V 1A = 10V 1C = 16V 1E = 25V 1H = 50V 2A = 100V 2D = 200V	2 significant figures + number of zeros Use "R" for decimal point	$C = \pm 0.25pF$ $D = \pm 0.5pF$ $F = \pm 1\%$ $J = \pm 5\%$ $K = \pm 10\%$ $M = \pm 20\%$ $Z = +80, -20\%$



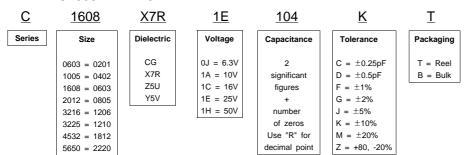
► ROHM: MCH182C104KKN



► TAIYO-YUDEN: TMK107BJ104K_T



▶ TDK : C1608X7R1E104KT



► VITRAMON: VJ0603Y104KXXMC

•
<u>C</u>
ng Packaging
C = 7" Reel Paper T = 7" Reel Plastic P = 13" Reel Plastic R = 13" Reel Plastic B = Bulk
rk

